

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner Sean Sprigg	Art Unit 3712	Page 1 of 1	

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L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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